

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
RELEASE 1.5Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [Quick Links](#)[IEEE Peer Review](#)[» Search Results](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
 - ☐ Establish IEEE Web Account
 - ☐ Access the IEEE Member Digital Library
- [Print Format](#)

Your search matched **2** of **963914** documents.A maximum of **2** results are displayed, **15** to a page, sorted by **Relevance** in **descending** order.

You may refine your search by editing the current search expression or entering a new one in the text box.

Then click **Search Again**.**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Quantitative and qualitative comparisons of PLC programs for a small testbed with a focus on human issues***Lucas, M.R.; Tilbury, D.M.;*

American Control Conference, 2002. Proceedings of the 2002, Volume: 5, 8-10 May 2002

Page(s): 4165 -4171 vol.5

[\[Abstract\]](#) [\[PDF Full-Text \(768 KB\)\]](#) **IEEE CNF****2 A translation method for ladder diagram with application to a manufacturing process***Hyung Seok Kim; Wook Hyun Kwon; Naehyuck Chang;*
Robotics and Automation, 1999. Proceedings. 1999 IEEE International Conference on, Volume: 1, 10-15 May 1999

Page(s): 793 -798 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(392 KB\)\]](#) **IEEE CNF**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved